FORM PTO/SB/08A/B (10-01) Substitute for PTO-1449A/B	**Attorney Docket Number**	**56136/DBP/N75**
INFORMATION DISCLOSURE STATEMENT BY APPLICANT (use as many sheets as necessary)	Application Number	N/A
	Filing Date	October 7, 2005
	Applicant(s)	Maxime Makarov, et al.
	Group Art Unit	N/A
	Examiner Name	N/A

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		International Search Report dated 02-01-2005 corresponding to PCT/FR2004/000557
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OTHER DOCUMENTS		
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